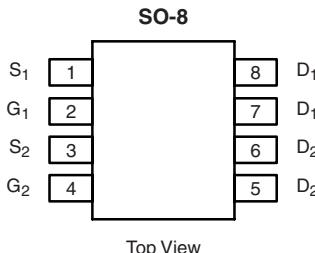


## Dual N-Channel 30-V (D-S) MOSFET with Schottky Diode

PRODUCT SUMMARY			
	V <sub>DS</sub> (V)	r <sub>DS(on)</sub> ( $\Omega$ )	I <sub>D</sub> (A)
Channel-1	30	0.022 at V <sub>GS</sub> = 10 V	7.5
		0.030 at V <sub>GS</sub> = 4.5 V	6.5
Channel-2		0.022 at V <sub>GS</sub> = 10 V	7.5
		0.028 at V <sub>GS</sub> = 4.5 V	6.5

SCHOTTKY PRODUCT SUMMARY		
V <sub>DS</sub> (V)	V <sub>SD</sub> (V) Diode Forward Voltage	I <sub>F</sub> (A)
30	0.50 V at 1.0 A	2.0



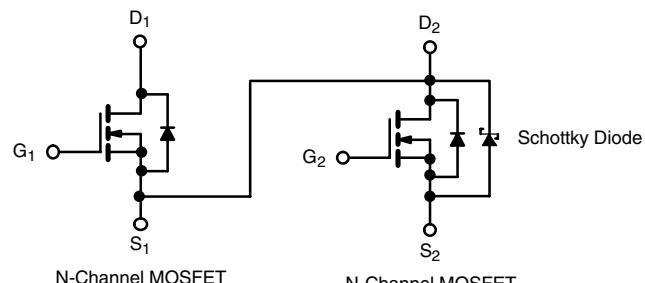
### FEATURES

- LITTLE FOOT® Plus Schottky
- Si4830DY Pin Compatible
- PWM Optimized
- 100 % R<sub>g</sub> Tested


**RoHS**  
COMPLIANT

### APPLICATIONS

- Asymmetrical Buck-Boost DC/DC Converter



Ordering Information: Si4370DY-T1-E3 (Lead (Pb)-free)

ABSOLUTE MAXIMUM RATINGS T <sub>A</sub> = 25 °C, unless otherwise noted						
Parameter	Symbol	10 secs		Steady State		Unit
		Channel-1	Channel-2	Channel-1	Channel-2	
Drain-Source Voltage	V <sub>DS</sub>			30		
Gate-Source Voltage	V <sub>GS</sub>	± 20	± 12	± 20	± 12	V
Continuous Drain Current (T <sub>J</sub> = 150 °C) <sup>a</sup>	I <sub>D</sub>	T <sub>A</sub> = 25 °C		7.5	5.7	A
		T <sub>A</sub> = 70 °C		6.0	4.6	
Pulsed Drain Current	I <sub>DM</sub>			30		
Continuous Source Current (Diode Conduction) <sup>a</sup>	I <sub>S</sub>			1.7	0.9	
Maximum Power Dissipation <sup>a</sup>	P <sub>D</sub>	T <sub>A</sub> = 25 °C		2.0	1.1	W
		T <sub>A</sub> = 70 °C		1.3	0.7	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>			- 55 to 150		°C

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	MOSFET		Schottky		Unit
		Typ	Max	Typ	Max	
Maximum Junction-to-Ambient <sup>a</sup>	R <sub>thJA</sub>	52	62.5	53	62.5	°C/W
		93	110	93	110	
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	35	40	35	40

Notes:

a. Surface Mounted on 1" x 1" FR4 Board.

**MOSFET SPECIFICATIONS**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ <sup>a</sup>	Max	Unit	
<b>Static</b>							
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Ch-1	1.0		3.0	
			Ch-2	0.8		2.0	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	Ch-1			$\pm 100$	
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$	Ch-2			$\pm 100$	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-1			1	
			Ch-2			100	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 85^\circ\text{C}$	Ch-1			15	
			Ch-2			2000	
On-State Drain Current <sup>b</sup>	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-1	20			
			Ch-2	20			
Drain-Source On-State Resistance <sup>b</sup>	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 7.5 \text{ A}$	Ch-1		0.014	0.022	
			Ch-2		0.015	0.022	
		$V_{GS} = 4.5 \text{ V}, I_D = 6.5 \text{ A}$	Ch-1		0.024	0.030	
			Ch-2		0.020	0.028	
Forward Transconductance <sup>b</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 7.5 \text{ A}$	Ch-1		19		
			Ch-2		21		
Diode Forward Voltage <sup>b</sup>	$V_{SD}$	$I_S = 1 \text{ A}, V_{GS} = 0 \text{ V}$	Ch-1		0.75	1.2	
			Ch-2		0.47	0.5	
<b>Dynamic<sup>a</sup></b>							
Total Gate Charge	$Q_g$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$	Ch-1		7	11	nC
Gate-Source Charge	$Q_{gs}$		Ch-2		11.5	18	
Gate-Drain Charge	$Q_{gd}$		Ch-1		2.9		
Gate Resistance	$R_g$		Ch-2		3.8		
Turn-On Delay Time	$t_{d(\text{on})}$		Ch-1		2.5		
Rise Time	$t_r$	$V_{DD} = 15 \text{ V}, R_L = 15 \Omega$ $I_D \geq 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 6 \Omega$	Ch-2		3.5		ns
Turn-Off Delay Time	$t_{d(\text{off})}$		Ch-1	0.5	1.5	1.9	
Fall Time	$t_f$		Ch-2	0.5	1.8	1.9	
Source-Drain Reverse Recovery Time	$t_{rr}$		Ch-1		9	15	
			Ch-2		10	17	
			Ch-1		10	17	
			Ch-2		19	30	
			Ch-1		40	66	
			Ch-2		9	15	
			Ch-1		9	15	
			Ch-2		28	45	

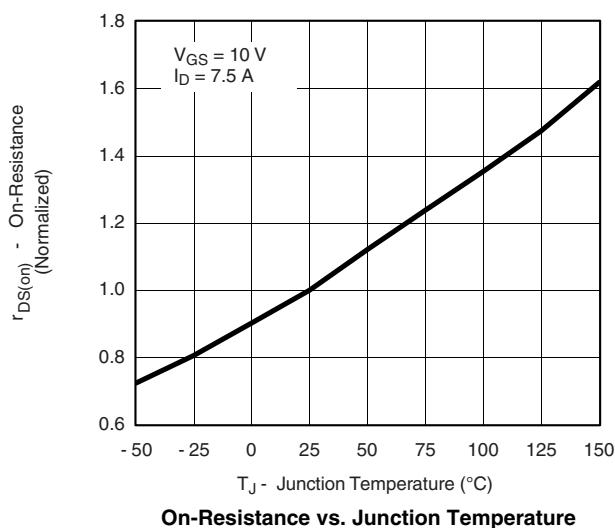
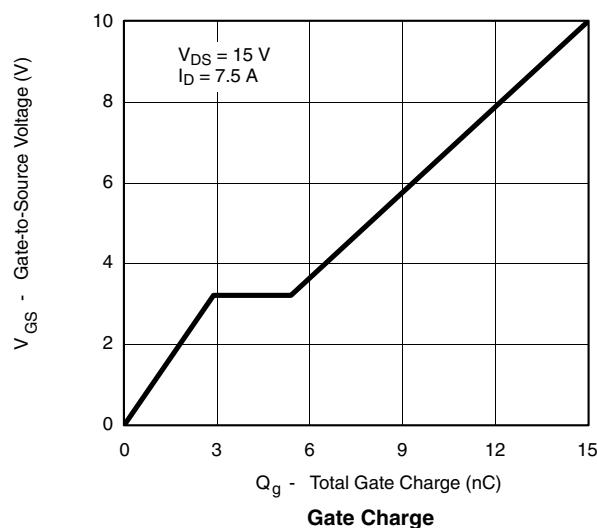
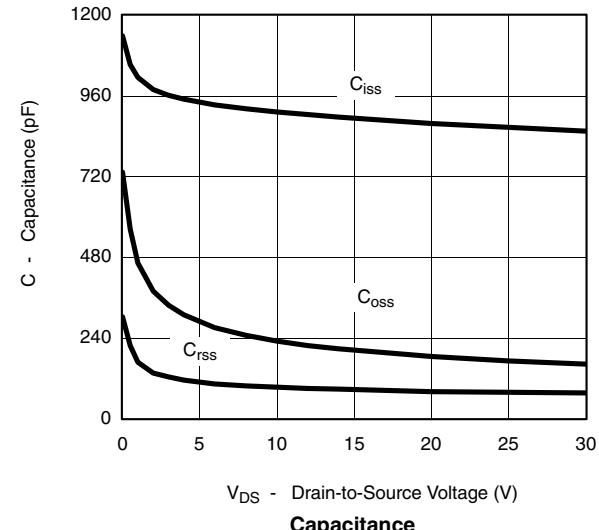
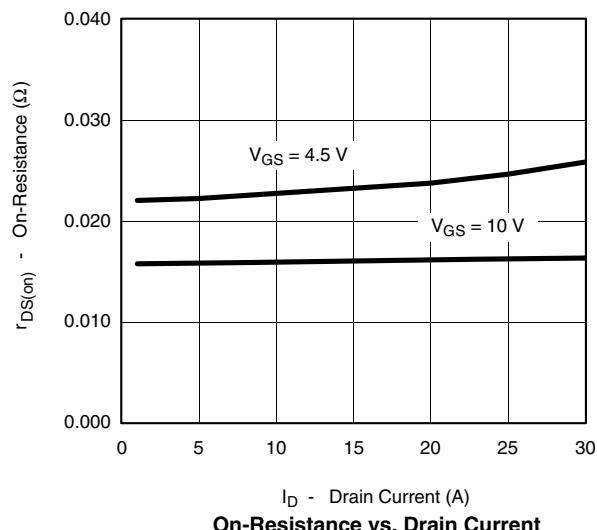
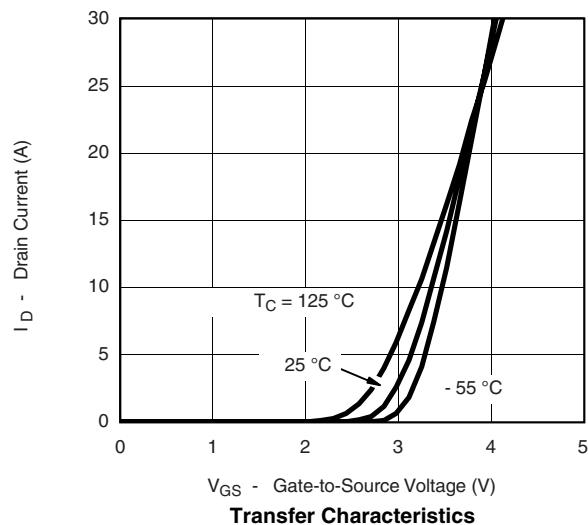
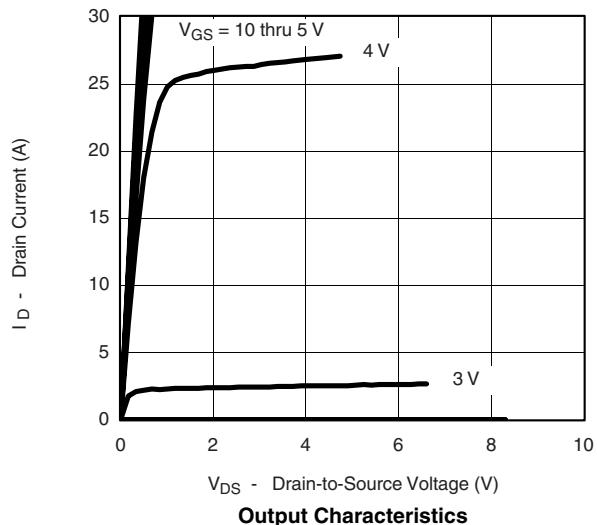
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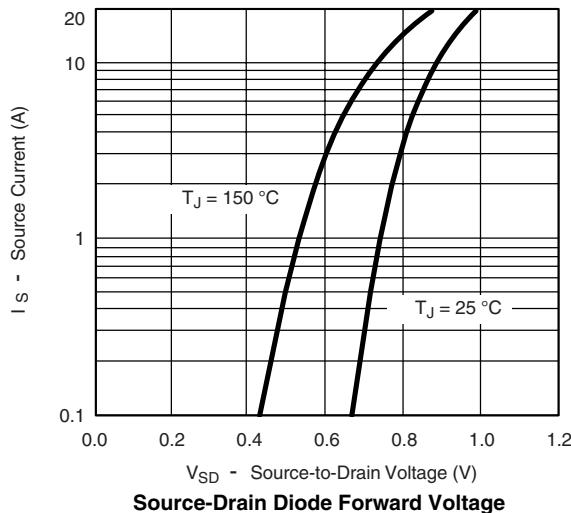
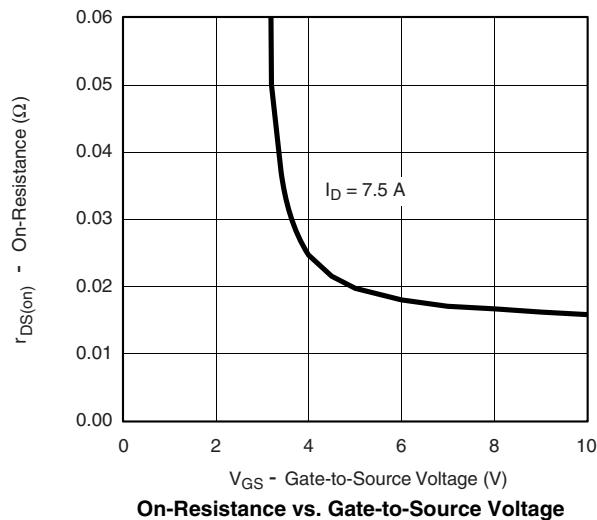
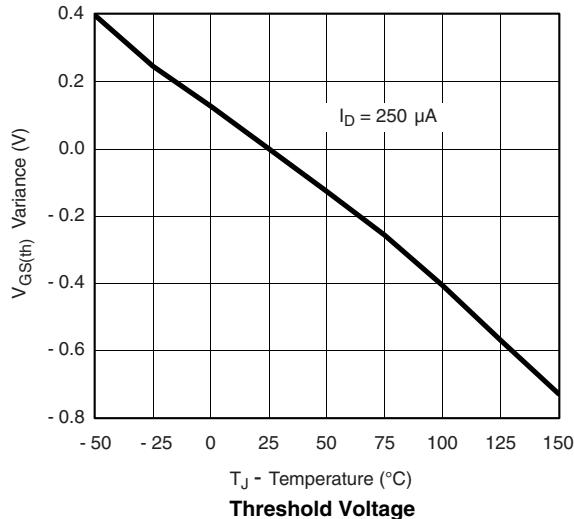
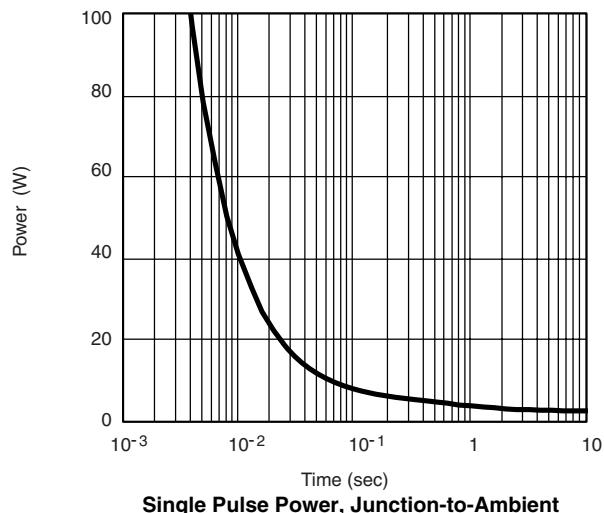
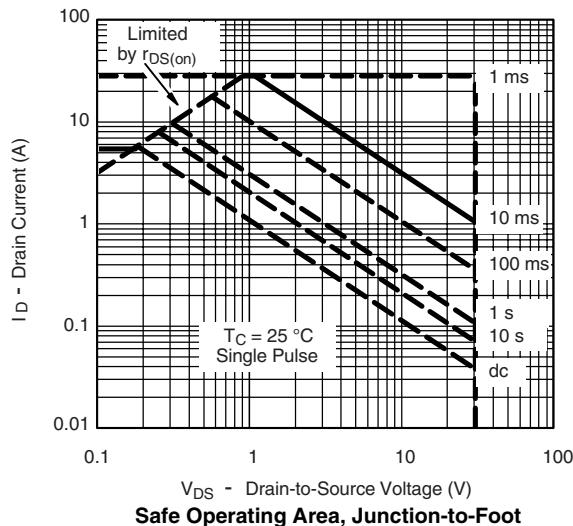
- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .

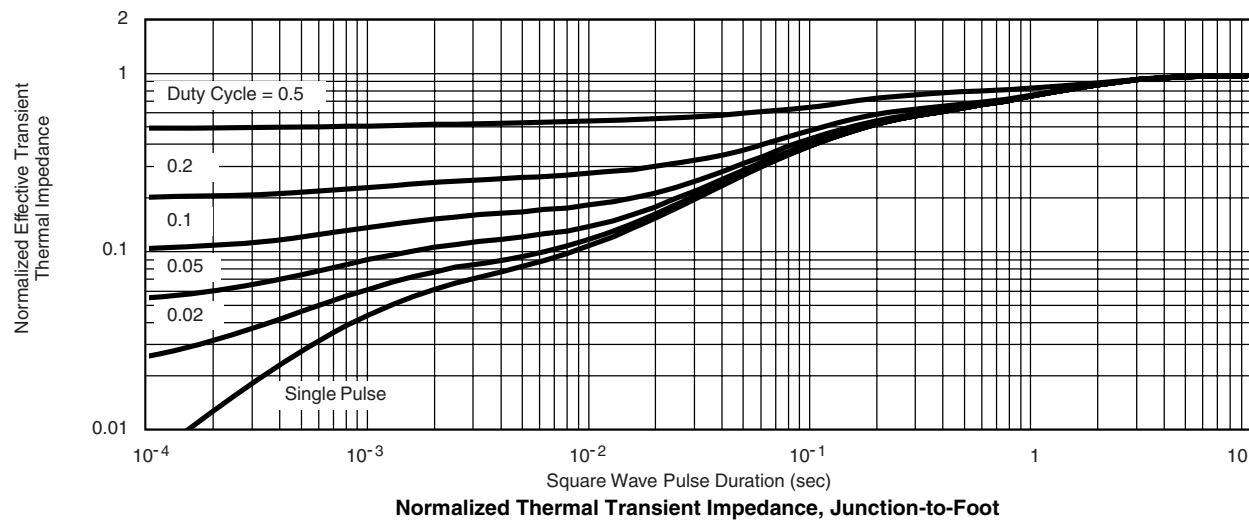
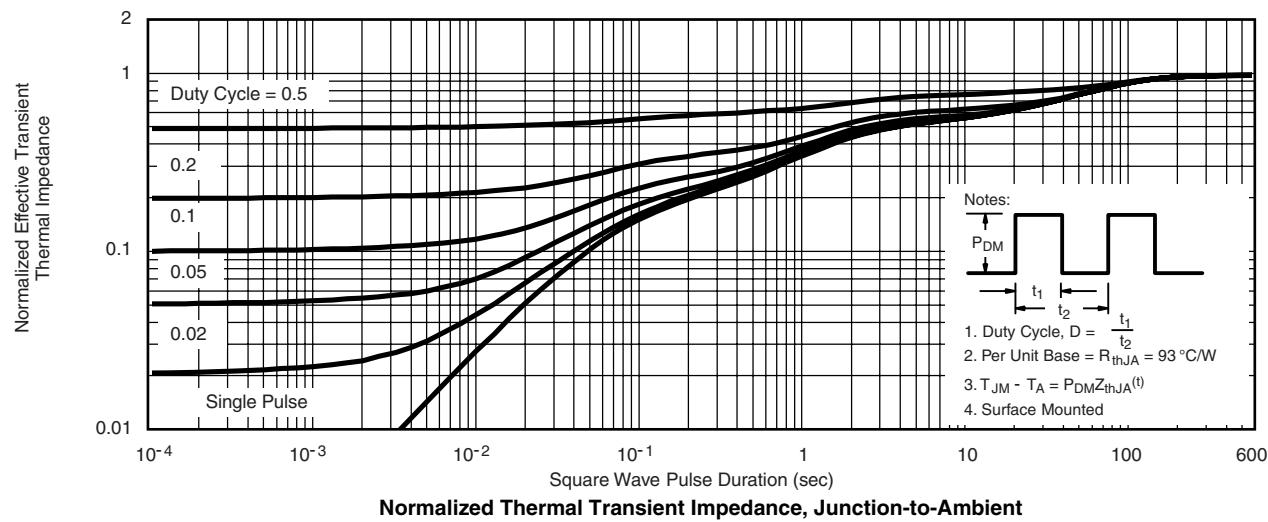
**SCHOTTKY SPECIFICATIONS**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

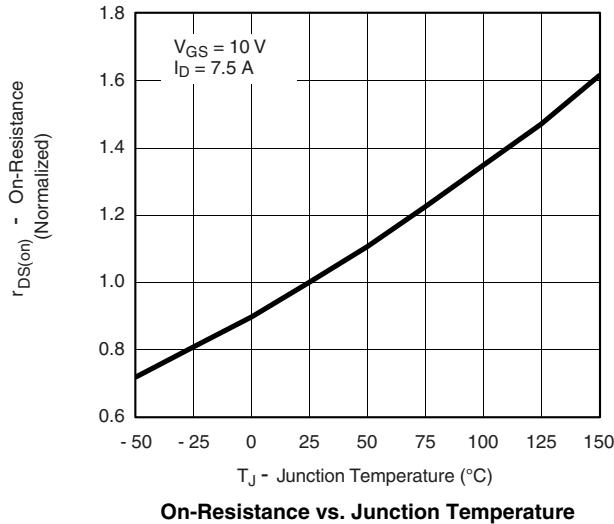
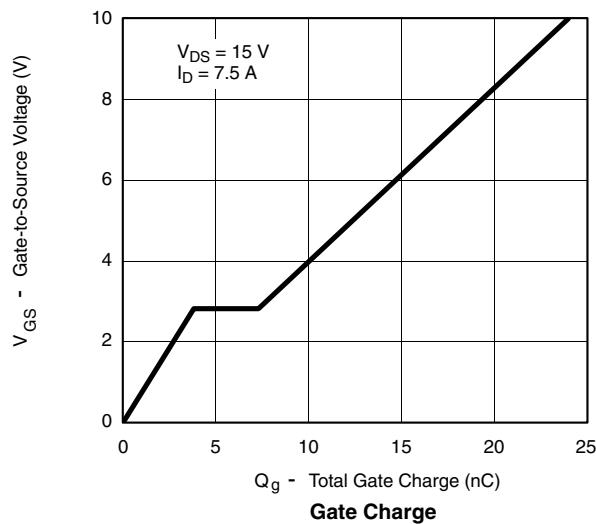
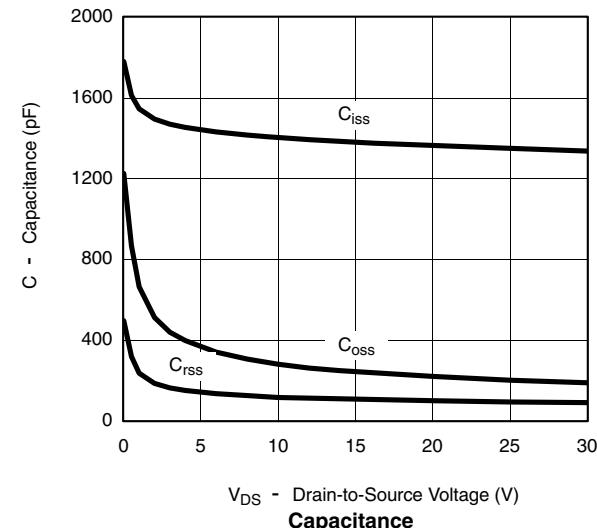
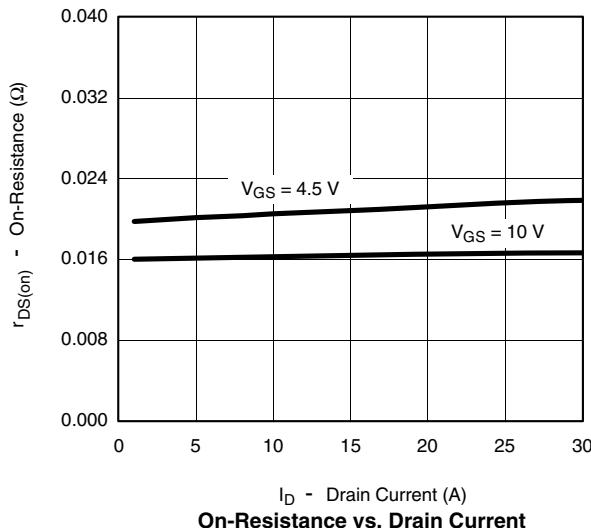
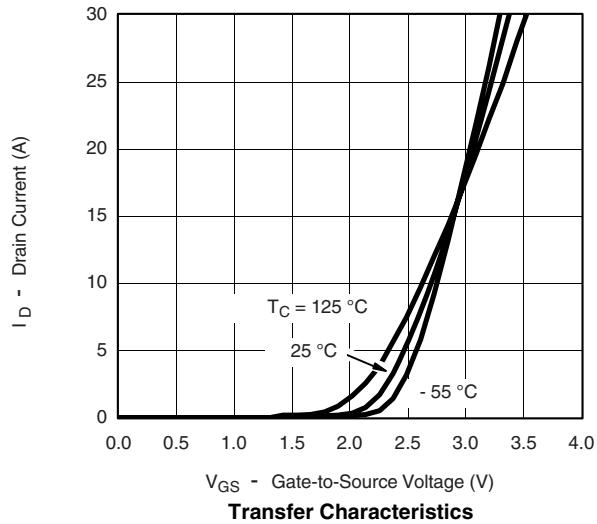
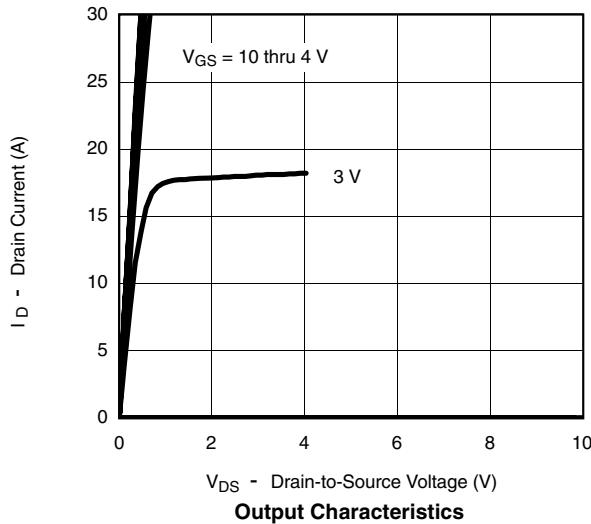
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Forward Voltage Drop	$V_F$	$I_F = 1.0 \text{ A}$		0.47	0.50	V
		$I_F = 1.0 \text{ A}, T_J = 125^\circ\text{C}$		0.36	0.42	
Maximum Reverse Leakage Current	$I_{rm}$	$V_r = 30 \text{ V}$		0.004	0.100	mA
		$V_r = 30 \text{ V}, T_J = 100^\circ\text{C}$		0.7	10	
		$V_r = -30 \text{ V}, T_J = 125^\circ\text{C}$		3.0	20	
Junction Capacitance	$C_T$	$V_r = 10 \text{ V}$		50		pF

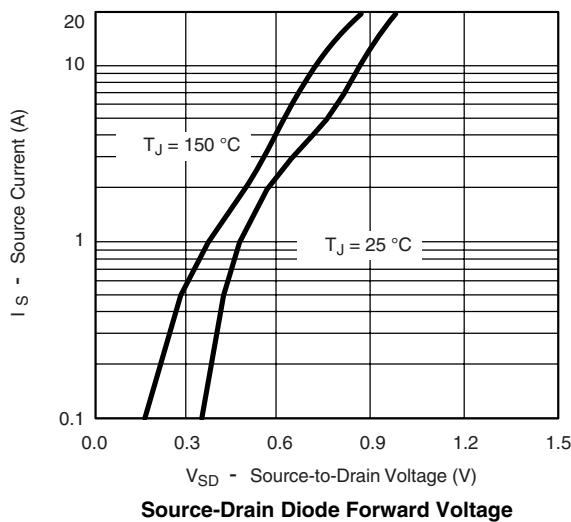
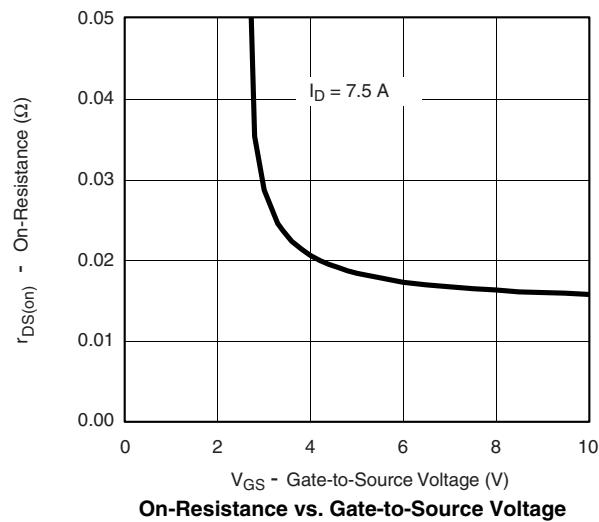
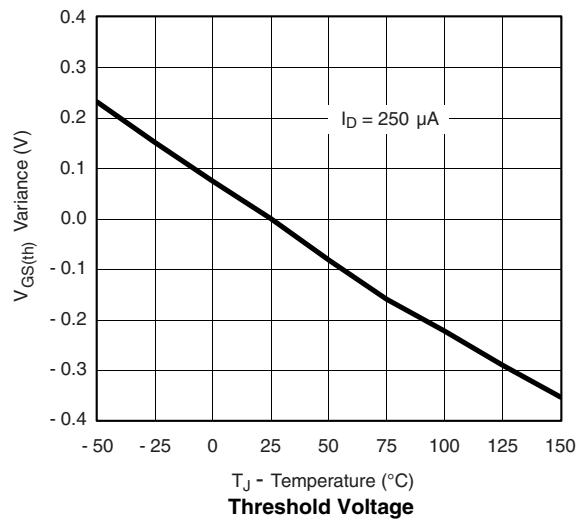
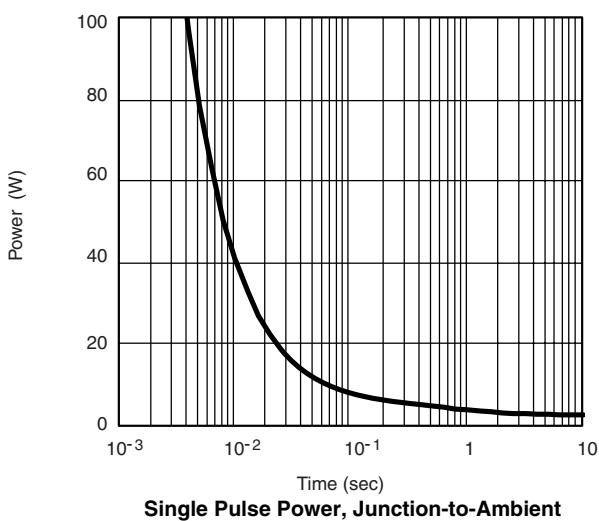
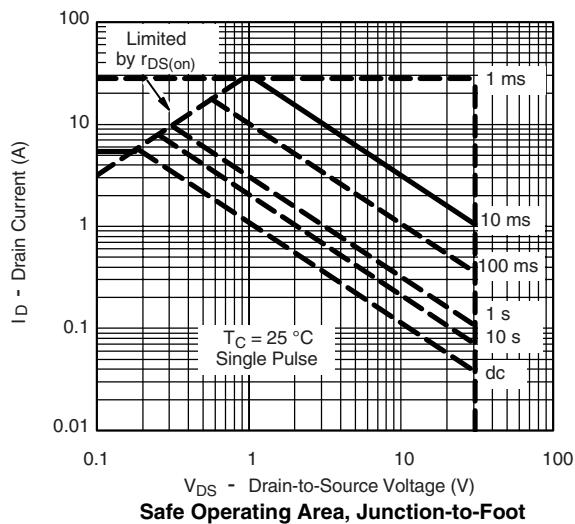
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

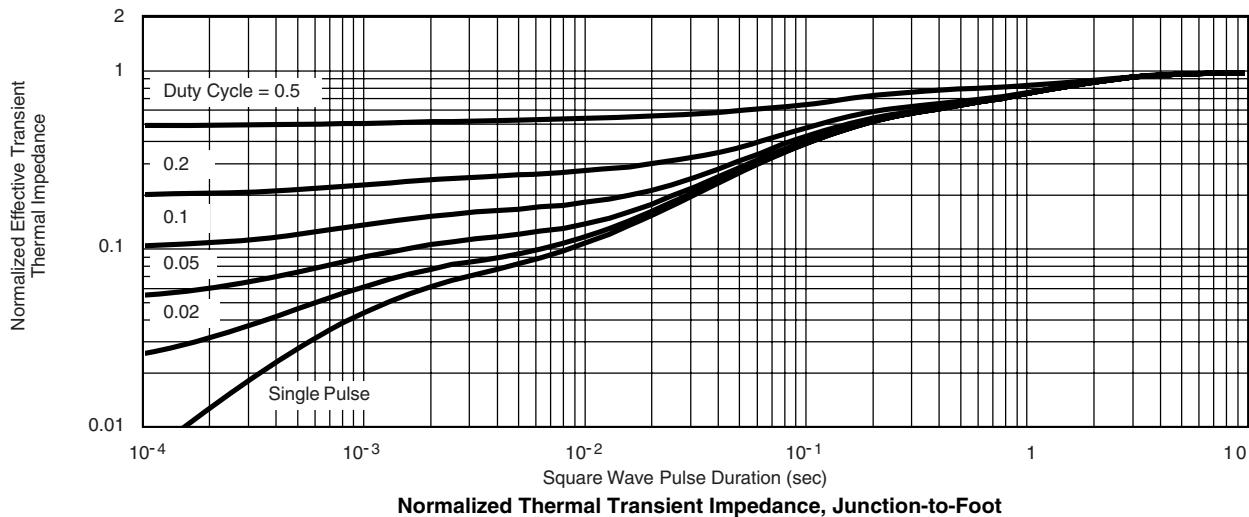
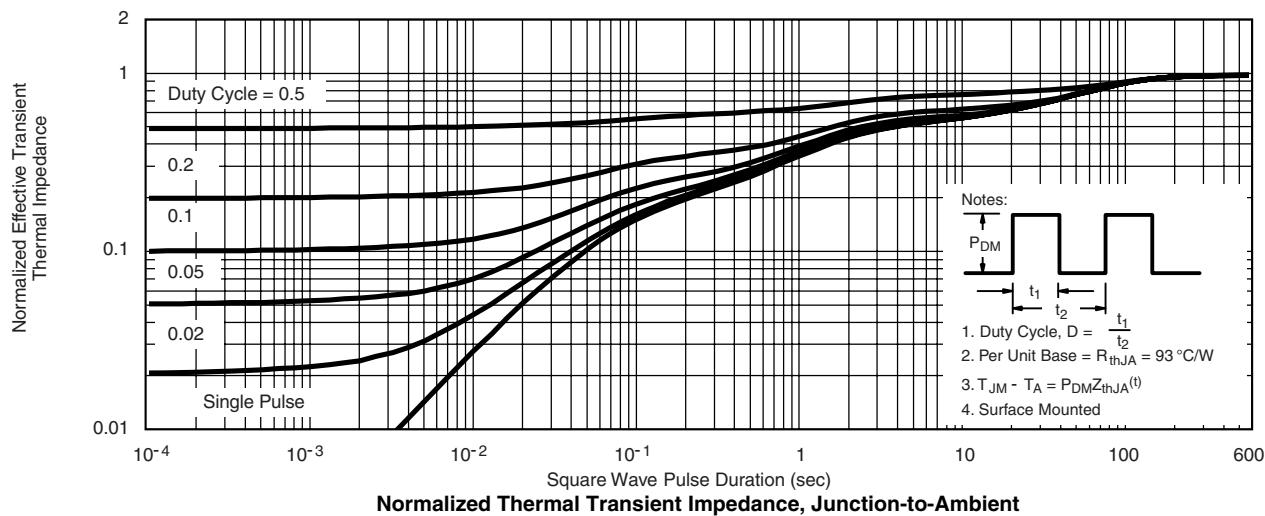
**MOSFET CHANNEL-1 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted


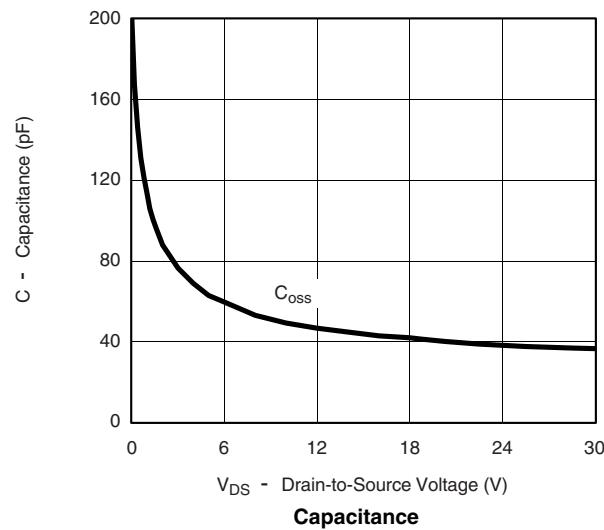
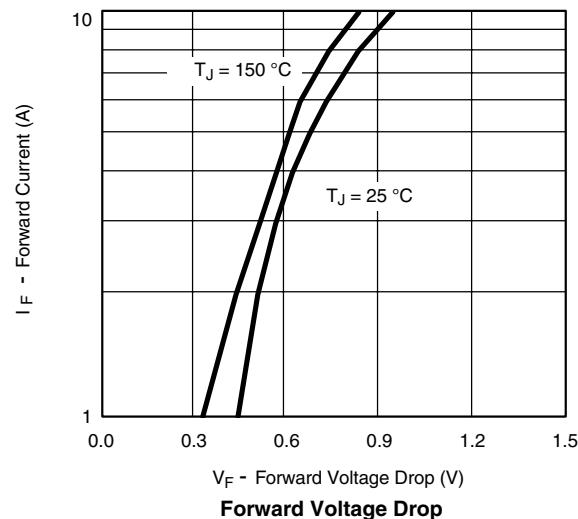
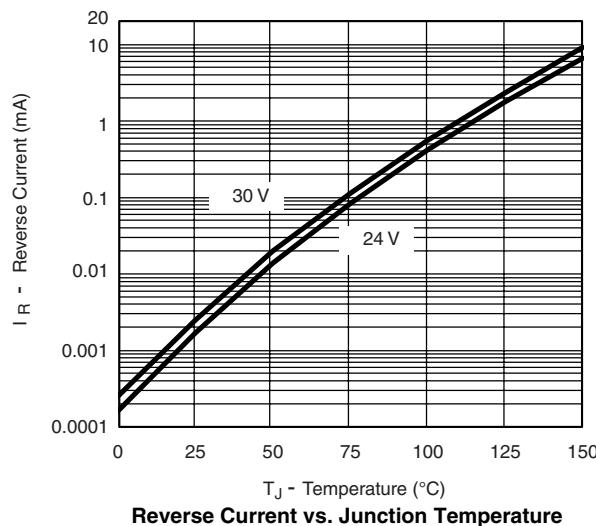
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**MOSFET CHANNEL-1 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted


**MOSFET CHANNEL-2 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

**MOSFET CHANNEL-2 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

**Source-Drain Diode Forward Voltage**

**On-Resistance vs. Gate-to-Source Voltage**

**Threshold Voltage**

**Single Pulse Power, Junction-to-Ambient**

**Safe Operating Area, Junction-to-Foot**

**MOSFET CHANNEL-2 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

**SCHOTTKY TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted


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